

PCTEST ENGINEERING LABORATORY, INC.

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## MEASUREMENT REPORT FCC PART 15.249 / ISED RSS-210 Bluetooth (Low Energy)

#### **Applicant Name:**

Samsung Electronics Co., Ltd. 129, Samsung-ro, Yeongtong-gu, Suwon-si Gyeonggi-do, 16677, Korea Date of Testing: 5/9-6/13/2018 Test Site/Location: PCTEST Lab. . Columbia, MD, USA Test Report Serial No.: 1M1805080100-04.A3L

## FCC ID: IC:

#### A3LETWV525

649E-ETWV525

APPLICANT:

## Samsung Electronics Co., Ltd.

Application Type: Model / HVIN: EUT Type: Max. RF Output Power: Frequency Range: FCC Classification: FCC Rule Part(s): ISED Specification: Test Procedure(s): Certification ET-WV525 Indoor Access Point 0.081 mW (-10.92 dBm) Peak Conducted 2402 – 2480MHz Low Power Communications Device Transmitter (DXX) Part 15 Subpart C (15.249) RSS-210 Issue 9 ANSI C63.10-2013, KDB 558074 D01 v04

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in ANSI C63.10-2013 and KDB 558074 D01 v04. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez President



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## 1.0 INTRODUCTION

## 1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Innovation, Science and Economic Development Canada.

## 1.2 PCTEST Test Location

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The measurement facility is compliant with the test site requirements specified in ANSI C63.4-2014.

#### **1.3** Test Facility / Accreditations Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.

- PCTEST is an ISO 17025-2005 accredited test facility under the American Association for Laboratory Accreditation (A2LA) with Certificate number 2041.01 for Specific Absorption Rate (SAR), Hearing Aid Compatibility (HAC) testing, where applicable, and Electromagnetic Compatibility (EMC) testing for FCC and Innovation, Science, and Economic Development Canada rules.
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC 17065-2012 by A2LA (Certificate number 2041.03) in all scopes of FCC Rules and ISED Standards (RSS).
- PCTEST facility is a registered (2451B) test laboratory with the site description on file with ISED.

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## 2.0 PRODUCT INFORMATION

## 2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Indoor Access Point FCC ID: A3LETWV525**. The data found in this test report was taken with the EUT operating in Bluetooth low energy mode. While in low energy mode, the Bluetooth transmitter hops pseudo-randomly between 40 channels. The data found in this report is representative of the device when it transmits on fixed channels with hopping disabled.

Test Device Serial No.: 5HX3S, AWX3S, BNX3S, 6PX3S, 5HX3S

## 2.2 Device Capabilities

This device contains the following capabilities:

802.11b/g/n/ac WLAN, 802.11a/n/ac UNII, Bluetooth (LE), Zigbee, Zwave

Ch.	Frequency (MHz)
0	2402
:	:
19	2440
:	:
39	2480

Table 2-1. Frequency / Channel Operations

## 2.3 Test Configuration

The EUT was tested per the guidance of ANSI C63.10-2013 and KDB 558074 D01 v04. ANSI C63.10-2013 was used to reference the appropriate EUT setup for radiated spurious emissions testing and AC line conducted testing. See Sections 3.2 for AC line conducted emissions test setups, 3.3 for radiated emissions test setups, and 7.2, 7.3, and 7.4 for antenna port conducted emissions test setups.

## 2.4 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and/or no modifications were made during testing.

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## 3.0 DESCRIPTION OF TESTS

## 3.1 Evaluation Procedure

The measurement procedures described in the American National Standard of Procedures for Compliance Testing of Unlicensed Wireless Devices (ANSI C63.10-2013) and the guidance provided in KDB 558074 D01 v04 were used in the measurement of the EUT.

Deviation from measurement procedure.....None

## 3.2 AC Line Conducted Emissions

The line-conducted facility is located inside a 10'x16'x9' shielded enclosure. The shielded enclosure is manufactured by ETS Lindgren RF Enclosures. The shielding effectiveness of the shielded room is in accordance with MIL-Std-285 or NSA 65-5. A 1m x 1.5m wooden table 80cm high is placed 40cm away from the vertical wall and 80cm away from the sidewall of the shielded room. Two 10kHz-30MHz,  $50\Omega/50\mu$ H Line-Impedance Stabilization Networks (LISNs) are bonded to the shielded room floor. Power to the LISNs is filtered by external high-current high-insertion loss power line filters. The external power line filter is an ETS Lindgren Model LPRX-4X30 (100dB Attenuation, 14kHz-18GHz) and the two EMI/RFI filters are ETS Lindgren Model LRW-2030-S1 (100dB Minimum Insertion Loss, 14kHz – 10GHz). These filters attenuate ambient signal noise from entering the measurement lines. These filters are also bonded to the shielded enclosure.

The EUT is powered from one LISN and the support equipment is powered from the second LISN. If the EUT is a DC-powered device, power will be derived from the source power supply it normally will be powered from and this supply line(s) will be connected to the second LISN. All interconnecting cables more than 1 meter were shortened to a 1 meter length by non-inductive bundling (serpentine fashion) and draped over the back edge of the test table. All cables were at least 40cm above the horizontal reference groundplane. Power cables for support equipment were routed down to the second LISN while ensuring that that cables were not draped over the second LISN.

Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. The RF output of the LISN was connected to the spectrum analyzer and exploratory measurements were made to determine the frequencies producing the maximum emission from the EUT. The spectrum was scanned from 150kHz to 30MHz with a spectrum analyzer. The detector function was set to peak mode for exploratory measurements while the bandwidth of the analyzer was set to 10kHz. The EUT, support equipment, and interconnecting cables were arranged and manipulated to maximize each emission. Once the worst case emissions have been identified, the one EUT cable configuration/arrangement and mode of operation that produced these emissions is used for final measurements on the same test site. The analyzer is set to CISPR quasi-peak and average detectors with a 9kHz resolution bandwidth for final measurements.

Line conducted emissions test results are shown in Section 7.7. The EMI Receiver mode of the Agilent MXE was used to perform AC line conducted emissions testing.

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#### 3.3 Radiated Emissions

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Figure 5.7 of Clause 5 in ANSI C63.4-2014. Absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections for measurements above 1GHz. An 80cm tall test table made of Styrodur is placed on top of the turn table. For measurements above 1GHz, an additional Styrodur pedestal is placed on top of the test table to bring the total table height to 1.5m.

For all measurements, the spectrum was scanned through all EUT azimuths and from 1 to 4 meter receive antenna height using a broadband antenna from 30MHz up to the upper frequency shown in 15.33 depending on the highest frequency generated or used in the device or on which the device operates or tunes. For frequencies above 1GHz, linearly polarized double ridge horn antennas were used. For frequencies below 30MHz, a calibrated loop antenna was used. When exploratory measurements were necessary, they were performed at 1 meter test distance inside the semi-anechoic chamber using broadband antennas, broadband amplifiers, and spectrum analyzers to determine the frequencies and modes producing the maximum emissions. Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. The test set-up was placed on top of the 1 x 1.5 meter table. The EUT, support equipment, and interconnecting cables were arranged and manipulated to maximize each emission. Appropriate precaution was taken to ensure that all emissions from the EUT were maximized and investigated. The system configuration, mode of operation, turntable azimuth, and receive antenna height was noted for each frequency found.

Final measurements were made in the semi-anechoic chamber using calibrated, linearly polarized broadband and horn antennas. The test setup was configured to the setup that produced the worst case emissions. The spectrum analyzer was set to investigate all frequencies required for testing to compare the highest radiated disturbances with respect to the specified limits. The turntable containing the EUT was rotated through 360 degrees and the height of the receive antenna was varied 1 to 4 meters and stopped at the azimuth and height producing the maximum emission. Each emission was maximized by changing the orientation of the EUT through three orthogonal planes and changing the polarity of the receive antenna, whichever produced the worst-case emissions.

## 3.4 Environmental Conditions

The temperature is controlled within range of 15°C to 35°C. The relative humidity is controlled within range of 10% to 75%. The atmospheric pressure is monitored within the range 86-106kPa (860-1060mbar).

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## 4.0 ANTENNA REQUIREMENTS

#### Excerpt from §15.203 of the FCC Rules/Regulations:

"An intentional radiator antenna shall be designed to ensure that no antenna other than that furnished by the responsible party can be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section."

- The antenna(s) of the EUT are **permanently attached**.
- There are no provisions for connection to an external antenna.

#### **Conclusion:**

The EUT complies with the requirement of §15.203.

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## 5.0 MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.10-2013. All measurement uncertainty values are shown with a coverage factor of k = 2 to indicate a 95% level of confidence. The measurement uncertainty shown below meets or exceeds the  $U_{\text{CISPR}}$  measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty (±dB)		
Conducted Bench Top Measurements	1.13		
Line Conducted Disturbance	3.09		
Radiated Disturbance (<1GHz)	4.98		
Radiated Disturbance (>1GHz)	5.07		
Radiated Disturbance (>18GHz)	5.09		

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## 6.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST). Measurements antennas used during testing were calibrated in accordance to the requirements of ANSI C63.5-2017.

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	WL25-1	Conducted Cable Set (25GHz)	6/14/2017	Annual	6/14/2018	WL25-1
Agilent	N9020A	MXA Signal Analyzer	1/24/2018	Annual	1/24/2019	US46470561
Agilent	N9030A	PXA Signal Analyzer (44GHz)	5/25/2018	Annual	5/25/2019	MY52350166
Sunol	DRH-118	Horn Antenna (1-18GHz)	8/11/2017	Biennial	8/11/2019	A050307
Emco	3115	Horn Antenna (1-18GHz)	3/28/2018	Biennial	3/28/2020	9704-5182
EMCO	3160-09	Small Horn (18 - 26.5GHz)	8/23/2016	Biennial	8/23/2018	135427
Keysight Technologies	N9038A	MXE EMI Receiver (3Hz-44GHz)	4/30/2018	Annual	4/30/2019	MY5640070
Pasternack	NMLC-2	Line Conducted Emissions Cable (NM)	1/23/2018	Annual	1/23/2019	NMLC-2
Rohde & Schwarz	ESU40	EMI Test Receiver (40GHz)	7/31/2017	Annual	7/31/2018	100348
Rohde & Schwarz	FSW67	Signal / Spectrum Analyzer	8/11/2017	Annual	8/11/2018	103200
Rohde & Schwarz	SFUNIT-Rx	Shielded Filter Unit	7/3/2017	Annual	7/3/2018	102134
Rohde & Schwarz	SFUNIT-Rx	Shielded Filter Unit	7/3/2017	Annual	7/3/2018	102133
Rohde & Schwarz	TS-PR8	Preamplifier (30MHz-8GHz)	10/19/2017	Annual	10/19/2018	102324
Rohde & Schwarz	TS-PR26	18-26.5 GHz Pre-Amplifier	1/24/2018	Annual	1/24/2019	100040
Seekonk	NC-100	Torque Wrench 5/16", 8" lbs	1/22/2018	Annual	1/22/2019	N/A
Solar Electronics	8012-50-R-24-BNC	Line Impedance Stabilization Network	8/14/2017	Biennial	8/14/2019	310233
Sunol	DRH-118	Horn Antenna (1-18GHz)	8/11/2017	Biennial	8/11/2019	A050307
Sunol Sciences	JB6	JB6 Antenna	9/27/2016	Biennial	9/27/2018	A082816

Table 6-1. Annual Test Equipment Calibration Schedule

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## 7.0 TEST RESULTS

## 7.1 Summary

Company Name:	Samsung Electronics Co., Ltd.
FCC ID:	A3LETWV525
IC:	<u>649E-ETWV525</u>
FCC Classification:	Low Power Communications Device Transmitter (DXX)

Number of Channels: <u>40</u>

FCC Part Section(s)	RSS Section(s)	Test Description	Test Limit	Test Condition	Test Result	Reference
2.1049	RSS-Gen [6.6]	Occupied Bandwidth	N/A		PASS	Section 7.2
2.1046	RSS-Gen [6.12]	Output Power Measurement	< 1 Watt	CONDUCTED	PASS	Sections 7.3
15.249(a)(e)	RSS-210 [B.10]	Fundamental Field Strength	< 50 mV/m		PASS	Section 7.4
15.205 15.209 15.249(a)(e)	RSS-Gen [8.9]	General Field Strength Limits (Restricted Bands and Radiated Emission Limits)	Emissions in restricted bands must meet the radiated limits detailed in 15.209 (RSS-Gen[8.9])	RADIATED	PASS	Sections 7.5, 7.6
15.207	RSS-Gen [8.8]	AC Conducted Emissions 150kHz – 30MHz	< FCC 15.207 limits (RSS- Gen[8.8])	SS- LINE CONDUCTED		Section 7.7

Table 7-1. Summary of Test Results

#### Notes:

- 1. All modes of operation were investigated. The test results shown in the following sections represent the worst case emissions.
- 2. The analyzer plots shown in this section were all taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables and attenuators used as part of the system to connect the EUT to the analyzer at all frequencies of interest.
- 3. All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables and attenuators.
- 4. For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST "Bluetooth LE Automation," Version 3.1.
- 5. For radiated band edge, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST "Chamber Automation," Version 0.2.8.

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#### **Occupied Bandwidth Measurement** 7.2 §2.1049; RSS-Gen (6.6)

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. The spectrum analyzers' "occupied bandwidth" measurement function was used to record the occupied bandwidth.

Frequency [MHz]	• •		Measured Bandwidth [kHz]	
2402	0	LE	1068.9	
2440	19	LE	1066.2	
2480	39	LE	1065.1	

Table 7-2. Occupied Bandwidth Measurement







#### Plot 7-1. Occupied Bandwidth Plot (Bluetooth (LE) - Ch. 0)

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KU RE 50Ω DC	Trig: F	SENSE:INT Freq: 2.440000000 GHz Free Run Avg Hold: 1: 26 dB	Radio Std:		Trace/Detector
10 dB/div Ref 15.00 dBr					
5.00 -5.00 -15.0 -25.0					Clear Write
-45.0					Average
-65.0					Max Hole
Center 2.44 GHz #Res BW 100 kHz Occupied Bandwidt		VBW 300 kHz Total Power		an 2 MHz ep 1 ms	Min Hol
1.	0662 MHz				Detecto Peak
Transmit Freq Error	40.986 kHz	% of OBW Powe	er 99.00 %	Au	uto <u>Ma</u>
x dB Bandwidth	688.2 kHz	x dB	-6.00 dB		
ISG			STATUS		

Plot 7-2. Occupied Bandwidth Plot (Bluetooth (LE) - Ch. 19)



Plot 7-3. Occupied Bandwidth Plot (Bluetooth (LE) – Ch. 39)

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# 7.3 Output Power Measurement §2.1046; RSS-Gen [6.12]

#### **Test Overview and Limits**

The transmitter antenna terminal of the EUT is connected to the input of a spectrum analyzer. Measurements are made while the EUT is operating at maximum power and at the appropriate frequencies.

#### The maximum permissible conducted output power is 1 Watt.

#### Test Procedure Used

ANSI C63.10-2013 – Section 11.9.1.1 KDB 558074 D01 v04 – Section 9.1.1

#### **Test Settings**

- 1. RBW = 3MHz
- 2. VBW = 50MHz
- 3. Span  $\ge$  3 x RBW
- 4. Sweep = auto couple
- 5. Detector = Peak
- 6. Trace mode = max hold
- 7. The trace was allowed to stabilize

#### Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.



Figure 7-2. Test Instrument & Measurement Setup

#### **Test Notes**

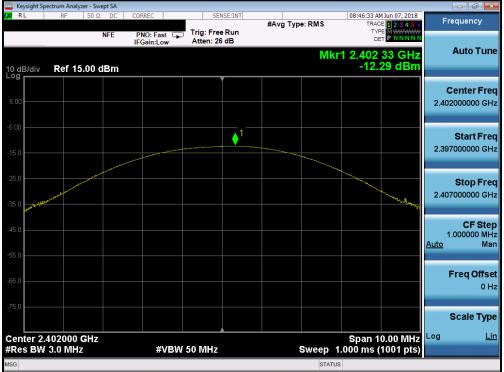
None

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Frequency	Channel	Channel Bluetooth		cted Power
[MHz]	] No. Mode	Mode	[dBm]	[mW]
2402	0	LE	-12.29	0.059
2440	19	LE	-10.92	0.081
2480	39	LE	-11.56	0.070

Table 7-3. Conducted Output Power Measurements (Bluetooth (LE))



Plot 7-4. Peak Power Plot (Bluetooth (LE) – Ch. 0)

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		zer - Swept SA								_	
LXI RL	RF	50 Ω DC	CORREC		ISE:INT	#Avg Typ	e: RMS	TRAC	MJun 07, 2018	Fred	quency
		NFE	PNO: Fast 🖵 IFGain:Low	Trig: Free Atten: 26				TYF DE			uto Tune
10 dB/div Log	Ref 15	5.00 dBm					Mkr	1 2.439 -10.	84 GHz 92 dBm	,	uto i une
5.00											e <b>nter Freq</b> 00000 GHz
-5.00			and the second se	•							Start Freq 00000 GHz
-25.0	and the second								and the second descent		<b>Stop Freq</b> 00000 GHz
-45.0										1.0 <u>Auto</u>	CF Step 00000 MHz Man
-65.0										Fr	r <b>eq Offsel</b> 0 Hz
-75.0	440000	011-						0		So Log	cale Type <sub>Lin</sub>
Center 2. #Res BW			#VBW	50 MHz			Sweep 1	Span 1 .000 m <u>s (</u>	0.00 MHz 1001 pts)	LUG	
MSG							STATUS	3			

Plot 7-5. Peak Power Plot (Bluetooth (LE) - Ch. 19)



Plot 7-6. Peak Power Plot (Bluetooth (LE) - Ch. 39)

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#### 7.4 Fundamental Field Strength Level Measurement §15.249(a)(e); RSS-210 (B.10)

Measurement is made while the EUT is operating in non-hopping transmission mode. The field strengths shown below were measured using a spectrum analyzer. Peak field strength measurements are performed in the analyzers' swept spectrum mode using a peak detector with RBW = 3MHz and VBW ≥ RBW.

The maximum permissible average field strength level is 50mV/m (93.98dB $\mu$ V/m). The maximum permissible peak field strength level is 500mV/m (113.98 dB $\mu$ V/m).

Frequency [MHz]	Detector	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	Limit [dBµV/m]	Margin [dB]
2402.00	Peak	V	135	319	-17.65	-3.18	86.17	93.98	-7.81
2440.00	Peak	V	135	319	-15.89	-3.36	87.75	93.98	-6.23
2480.00	Peak	V	140	132	-17.64	-2.89	86.46	93.98	-7.52

Table 7-4. Field Strength Measurements

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# 7.5 Radiated Spurious Emission Measurements §15.205 §15.209 §15.249(a)(e); RSS-Gen [8.9]

#### **Test Overview and Limit**

All out of band radiated spurious emissions are measured with a spectrum analyzer connected to a receive antenna while the EUT is operating at maximum power and at the appropriate frequencies. Only the radiated emissions of the configuration that produced the worst case emissions are reported in this section.

All out of band emissions appearing in a restricted band as specified in Section 15.205 of the Title 47 CFR and Table 6 of RSS-Gen (8.10) must not exceed the limits shown in Table 7-5 per Section 15.209 and RSS-Gen (8.9).

Frequency	Field Strength [μV/m]	Measured Distance [Meters]
0.009 – 0.490 MHz	2400/F (kHz)	300
0.490 – 1.705 MHz	24000/F (kHz)	30
1.705 – 30.00 MHz	30	30
30.00 – 88.00 MHz	100	3
88.00 – 216.0 MHz	150	3
216.0 – 960.0 MHz	200	3
Above 960.0 MHz	500	3

Table 7-5. Radiated Limits

#### **Test Procedures Used**

ANSI C63.10-2013 – Section 6.6.4.3

KDB 558074 D01 v04 - Section 12.1, 12.2.7

#### **Test Settings**

#### Average Field Strength Measurements

- 1. Analyzer center frequency was set to the frequency of the radiated spurious emission of interest
- 2. RBW = 1MHz
- 3. VBW = 3kHz > 1/T
- 4. Averaging type was set to RMS to ensure that video filtering was applied in the power domain
- 5. Detector = peak
- 6. Sweep time = auto
- 7. Trace mode = max hold
- 8. Trace was allowed to run for at least 50 times (1/duty cycle) traces

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#### Peak Field Strength Measurements

- 1. Analyzer center frequency was set to the frequency of the radiated spurious emission of interest
- 2. RBW is set depending on measurement frequency, as specified in Table 7-6 below
- 3. VBW = 3MHz
- 4. Detector = peak
- 5. Sweep time = auto couple
- 6. Trace mode = max hold
- 7. Trace was allowed to stabilize

Frequency	RBW
9 – 150kHz	200 – 300Hz
0.15 – 30MHz	9 – 10kHz
30 – 1000MHz	100 – 120kHz
> 1000MHz	1MHz

Table 7-6. RBW as a Function of Frequency

#### Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

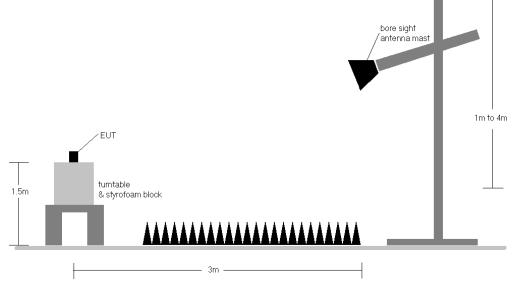


Figure 7-3. Radiated Test Setup >1GHz

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- The optional test procedures for antenna port conducted measurements of unwanted emissions per the guidance of KDB 558074 D01 v04 were not used to evaluate this device for compliance to radiated limits. All radiated spurious emissions levels were measured in a radiated test setup.
- 2. All emissions lying in restricted bands specified in §15.205 and Section 8.10 of RSS-Gen are below the limit shown in Table 7-5.
- 3. The antenna is manipulated through typical positions, polarity and length during the tests. The EUT is manipulated through three orthogonal planes.
- 4. This unit was tested while powered by an AC power source.
- 5. The spectrum is measured from 9kHz to the 10th harmonic of the fundamental frequency of the transmitter using CISPR quasi peak detector below 1GHz. Above 1 GHz, average and peak measurements were taken using linearly polarized horn antennas. The worst-case emissions are reported however emissions whose levels were not within 20dB of the respective limits were not reported.
- 6. Average measurements were recorded using a VBW of 3kHz, per Section 12.2.5.3 of KDB 558074 D01 v04 and Section 4.1.4.2.3 of ANSI C63.10-2013, since 1/T is equal to just under 3kHz. This method was used because the EUT could not be configured to operate with a duty cycle > 98%. Both average and peak measurements were made using a peak detector
- 7. Emissions below 18GHz were measured at a 3 meter test distance while emissions above 18GHz were measured at a 1 meter test distance with the application of a distance correction factor.
- 8. No significant radiated band edge emissions were found in the 2310 2390MHz restricted band.
- 9. The "-" shown in the following RSE tables are used to denote a noise floor measurement.

#### **Sample Calculations**

#### **Determining Spurious Emissions Levels**

- Field Strength Level [dBµV/m] = Analyzer Level [dBm] + 107 + AFCL [dB/m]
- AFCL [dB/m] = Antenna Factor [dB/m] + Cable Loss [dB]
- $\circ \quad \text{Margin}_{[dB]} = \text{Field Strength Level}_{[dB\mu V/m]} \text{Limit}_{[dB\mu V/m]}$

#### Radiated Band Edge Measurement Offset

• The amplitude offset shown in the radiated restricted band edge plots in Section 7.6 was calculated using the formula:

Offset (dB) = (Antenna Factor + Cable Loss + Attenuator) – Preamplifier Gain

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# Radiated Spurious Emission Measurements §15.205 §15.209 §15.249(a)(e); RSS-Gen [8.9]

Bluetooth Mode:	LE
Distance of Measurements:	3 Meters
Operating Frequency:	2402MHz
Channel:	0

Frequency [MHz]	Detector	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	Limit [dBµV/m]	Margin [dB]
4804.00	Avg	V	279	357	-65.51	2.42	43.91	53.98	-10.06
4804.00	Peak	V	279	357	-59.41	2.42	50.01	73.98	-23.96
12010.00	Avg	V	-	-	-78.43	13.48	42.05	53.98	-11.93
12010.00	Peak	V	-	-	-66.16	13.48	54.32	73.98	-19.66

Table 7-7. Radiated Measurements @ 3 meters

Bluetooth Mode:	LE
Distance of Measurements:	3 Meters
Operating Frequency:	2440MHz
Channel:	19

Frequency [MHz]	Detector	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	Limit [dBµV/m]	Margin [dB]
4880.00	Avg	V	265	355	-62.10	3.27	48.17	53.98	-5.81
4880.00	Peak	V	265	355	-60.39	3.27	49.88	73.98	-24.10
7320.00	Avg	V	-	-	-78.58	9.70	38.12	53.98	-15.86
7320.00	Peak	V	-	-	-66.24	9.70	50.46	73.98	-23.52
12200.00	Avg	V	-	-	-79.02	14.01	41.99	53.98	-11.99
12200.00	Peak	V	-	-	-66.05	14.01	54.96	73.98	-19.02

Table 7-8. Radiated Measurements @ 3 meters

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# Radiated Spurious Emission Measurements §15.205 §15.209 §15.249(a)(e); RSS-Gen [8.9]

Bluetooth Mode:	LE
Distance of Measurements:	3 Meters
Operating Frequency:	2480MHz
Channel:	39

Frequency [MHz]	Detector	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	Limit [dBµV/m]	Margin [dB]
4960.00	Avg	V	237	119	-65.00	2.62	44.62	53.98	-9.36
4960.00	Peak	V	237	119	-59.77	2.62	49.85	73.98	-24.13
7440.00	Avg	V	163	227	-78.05	-78.05 9.48 38.43		53.98	-15.55
7440.00	Peak	V	163	227	-65.49	9.48	50.99	73.98	-22.99
12400.00	Avg	V	-	-	-79.16	12.93	40.77	53.98	-13.21
12400.00	Peak	V	-	-	-65.50	12.93	54.43	73.98	-19.55

Table 7-9. Radiated Measurements @ 3 meters

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# 7.6 Radiated Restricted Band Edge Measurements §15.205 §15.209 §15.249(a)(e); RSS-Gen [8.9]

The radiated restricted band edge measurements are measured with an EMI test receiver connected to the receive antenna while the EUT is transmitting.

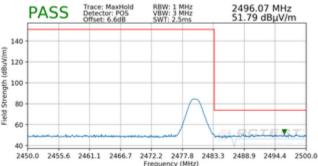
The amplitude offset shown in the following plots for average measurements was calculated using the formula:

Offset (dB) = (Antenna Factor + Cable Loss + Attenuator) – Preamplifier Gain

Bluetooth Mode:	LE
Measurement Distance:	3 Meters
Operating Frequency:	2480MHz
Channel:	39



Plot 7-7. Radiated Restricted Upper Band Edge Measurement (Average)



Plot 7-8. Radiated Restricted Upper Band Edge Measurement (Peak)

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#### 7.7 Line-Conducted Test Data §15.207; RSS-Gen [8.8]

#### **Test Overview and Limit**

All AC line conducted spurious emissions are measured with a receiver connected to a grounded LISN while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All data rates and modes were investigated for conducted spurious emissions. Only the conducted emissions of the configuration that produced the worst case emissions are reported in this section.

# All conducted emissions must not exceed the limits shown in the table below, per Section 15.207 and RSS-Gen (8.8).

Frequency of emission	Conducted	Limit (dBµV)
(MHz)	Quasi-peak	Average
0.15 – 0.5	66 to 56*	56 to 46*
0.5 – 5	56	46
5 – 30	60	50

Table 7-10. Conducted Limits

\*Decreases with the logarithm of the frequency.

#### **Test Procedures Used**

ANSI C63.10-2013, Section 6.2

#### Test Settings

#### **Quasi-Peak Field Strength Measurements**

- 1. Analyzer center frequency was set to the frequency of the spurious emission of interest
- 2. RBW = 9kHz (for emissions from 150kHz 30MHz)
- 3. Detector = quasi-peak
- 4. Sweep time = auto couple
- 5. Trace mode = max hold
- 6. Trace was allowed to stabilize

#### Average Field Strength Measurements

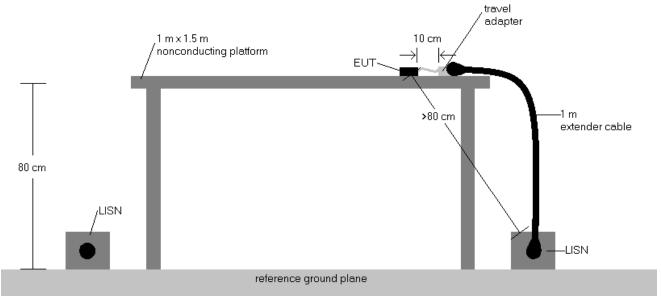
- 1. Analyzer center frequency was set to the frequency of the spurious emission of interest
- 2. RBW = 9kHz (for emissions from 150kHz 30MHz)
- 3. Detector = RMS
- 4. Sweep time = auto couple
- 5. Trace mode = max hold
- 6. Trace was allowed to stabilize

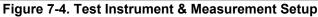
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### Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.





#### Test Notes

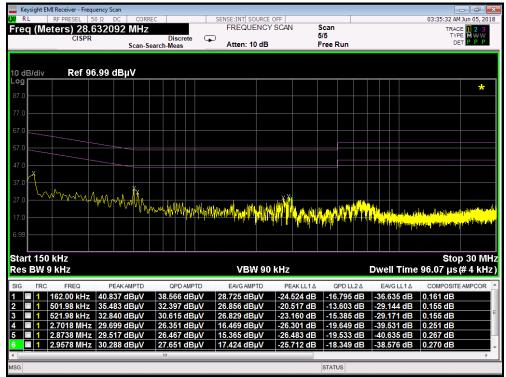
- All modes of operation were investigated and the worst-case emissions are reported using mid channel. The emissions found were not affected by the choice of channel used during testing.
- 2. The limit for an intentional radiator from 150kHz to 30MHz are specified in Part 15.207 and RSS-Gen (8.8).
- 3. Corr. (dB) = Cable loss (dB) + LISN insertion factor (dB)
- 4. QP/AV Level (dB $\mu$ V) = QP/AV Analyzer/Receiver Level (dB $\mu$ V) + Corr. (dB)
- 5. Margin (dB) = QP/AV Limit (dB $\mu$ V) QP/AV Level (dB $\mu$ V)
- 6. Traces shown in plot are made using a peak detector.
- 7. Deviations to the Specifications: None.

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Plot 7-10. Line Conducted Plot with Bluetooth LE (N)

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## 8.0 CONCLUSION

The data collected relate only the item(s) tested and show that the **Samsung Indoor Access Point FCC ID: A3LETWV525** is in compliance with Part 15 Subpart C (15.249) of the FCC Rules and RSS-210 of the Innovation, Science and Economic Development Canada Rules.

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